

#### Features

- 3.3V operation (3.0V 3.6V)
- High speed
  - t<sub>AA</sub> = 10 ns
- Low active power
  - 540 mW (max., 12 ns)
- Very Low standby power
  - 330 μW (max., "L" version)
- Automatic power-down when deselected
- Independent Control of Upper and Lower bytes
- Available in 44-pin TSOP II and 400-mil SOJ

#### **Functional Description**

The CY7C1020V is a high-performance CMOS static RAM organized as 32,768 words by 16 bits. This device has an automatic power-down feature that significantly reduces power consumption when deselected.

Writing to the device is accomplished by taking chip enable  $(\overline{CE})$  and write enable  $(\overline{WE})$  inputs LOW. If byte low enable

# CY7C1020V

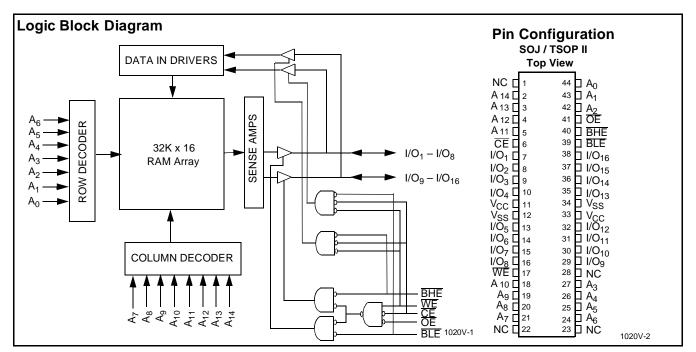
# $\begin{array}{c} 32K \ x \ 16 \ Static \ RAM \\ (BLE) \ \text{is LOW, then data from I/O pins (I/O_1 \ through \ I/O_8), is} \end{array}$

(BLE) is LOW, then data from I/O pins (I/O<sub>1</sub> through I/O<sub>8</sub>), is written into the location specified on the address pins (A<sub>0</sub> through A<sub>14</sub>). If byte high enable (BHE) is LOW, then data from I/O pins (I/O<sub>9</sub> through I/O<sub>16</sub>) is written into the location specified on the address pins (A<sub>0</sub> through A<sub>14</sub>).

Reading from the device is accomplished by taking chip enable ( $\overline{CE}$ ) and output enable ( $\overline{OE}$ ) LOW while forcing the write enable ( $\overline{WE}$ ) HIGH. If byte low enable ( $\overline{BLE}$ ) is LOW, then data from the memory location specified by the address pins will appear on I/O<sub>1</sub> to I/O<sub>8</sub>. If byte high enable ( $\overline{BHE}$ ) is LOW, then data from memory will appear on I/O<sub>9</sub> to I/O<sub>16</sub>. See the truth table at the back of this datasheet for a complete description of read and write modes.

The input/output pins ( $I/O_1$  through  $I/O_{16}$ ) are placed in a high-impedance state when the device is deselected ( $\overline{CE}$  HIGH), the outputs are disabled ( $\overline{OE}$  HIGH), the  $\overline{BHE}$  and  $\overline{BLE}$  are disabled ( $\overline{BHE}$ ,  $\overline{BLE}$  HIGH), or during a write operation ( $\overline{CE}$  LOW, and  $\overline{WE}$  LOW).

The CY7C1020V is available in standard 44-pin TSOP type II and 400-mil-wide SOJ packages.



#### **Selection Guide**

		7C1020V-10	7C1020V-12	7C1020V-15	7C1020V-20
Maximum Access Time (ns)		10	12	15	20
Maximum Operating Current (mA)		130	120	110	100
	L	100	90	80	70
Maximum CMOS Standby Current (mA)		1	1	1	1
	L	0.1	0.1	0.1	0.1

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## **Maximum Ratings**

(Above which the useful life may be impaired. For user guide-lines, not tested.)
Storage Temperature65°C to +150°C
Ambient Temperature with Power Applied55°C to +125°C
Supply Voltage on $V_{CC}$ to Relative GND <sup>[1]</sup> –0.5V to +4.6V
DC Voltage Applied to Outputs in High Z State <sup>[1]</sup> 0.5V to V <sub>CC</sub> +0.5V DC Input Voltage <sup>[1]</sup> 0.5V to V <sub>CC</sub> +0.5V

Current into Outputs (LOW)	20 mA
Static Discharge Voltage (per MIL-STD-883, Method 3015)	.>2001V
Lotoh Un Current	200 m

Latch-Up Current.....>200 mA

#### **Operating Range**

Range	Ambient Temperature <sup>[2]</sup>	v <sub>cc</sub>	
Commercial	0°C to +70°C	3.0V - 3.6V	
Industrial	–40°C to +85°C	3.0V - 3.6V	

#### Electrical Characteristics Over the Operating Range

		Test Conditions		7C102	20V-10	7C102	20V-12	
Parameter	Description			Min.	Max.	Min.	Max.	Unit
V <sub>OH</sub>	Output HIGH Voltage	$V_{CC}$ = Min., $I_{OH}$ = - 4.0 mA		2.4		2.4		V
V <sub>OL</sub>	Output LOW Voltage	V <sub>CC</sub> = Min., I <sub>OL</sub> = 8.0 mA			0.4		0.4	V
V <sub>IH</sub>	Input HIGH Voltage			2.0	V <sub>CC</sub> + 0.3V	2.0	V <sub>CC</sub> + 0.3V	V
V <sub>IL</sub>	Input LOW Voltage <sup>[1]</sup>			-0.5	0.8	-0.5	0.8	V
I <sub>IX</sub>	Input Load Current	$GND \le V_I \le V_{CC}$	-1	+1	-1	+1	μΑ	
I <sub>OZ</sub>	Output Leakage Current	$GND \leq V_I \leq V_{CC}$ , Output Disat	bled	-2	+2	-2	+2	μΑ
I <sub>CC</sub>	V <sub>CC</sub> Operating Supply Current	V <sub>CC</sub> = Max.			130		120	mA
		$I_{OUT} = 0 \text{ mÅ},$ f = f <sub>MAX</sub> = 1/t <sub>RC</sub>	L		100		90	mA
I <sub>SB1</sub>	Automatic CE	Max. $V_{CC}$ , $\overline{CE} \ge V_{IH}$			15		15	mA
	Power-Down Current — TTL Inputs	$V_{IN} \ge V_{IH} \text{ or}$ $V_{IN} \le V_{IL}, f = f_{MAX}$	L		7		7	mA
I <sub>SB2</sub>	Automatic CE	Max. V <sub>CC</sub> ,			1		1	mA
	Power-Down Current —CMOS Inputs	$\label{eq:central_constraint} \begin{array}{l} \overline{CE} \geq V_{CC} - 0.3 \text{V}, \\ \overline{V_{IN}} \geq V_{CC} - 0.3 \text{V}, \\ \text{or } V_{IN} \leq 0.3 \text{V}, \text{ f=0} \end{array} \right.$			100		100	μA

Notes:

1.  $V_{IL}$  (min.) = -2.0V for pulse durations of less than 20 ns. 2.  $T_A$  is the "instant on" case temperature.



#### Electrical Characteristics Over the Operating Range (continued)

				7C102	20V-15	0V-15 7C1020V-20		
Parameter	Description	Test Conditions		Min.	Max.	Min.	Max.	Unit
V <sub>OH</sub>	Output HIGH Voltage	V <sub>CC</sub> = Min., I <sub>OH</sub> = - 4.0 mA		2.4		2.4		V
V <sub>OL</sub>	Output LOW Voltage	V <sub>CC</sub> = Min., I <sub>OL</sub> = 8.0 mA			0.4		0.4	V
V <sub>IH</sub>	Input HIGH Voltage			2.0	V <sub>CC</sub> + 0.3V	2.0	V <sub>CC</sub> + 0.3V	V
V <sub>IL</sub>	Input LOW Voltage <sup>[1]</sup>			-0.5	0.8	-0.5	0.8	V
I <sub>IX</sub>	Input Load Current	$GND \le V_I \le V_{CC}$	$GND \leq V_1 \leq V_{CC}$			-1	+1	μA
I <sub>OZ</sub>	Output Leakage Current	$GND \le V_I \le V_{CC}$ , Output Disa	bled	-2	+2	-2	+2	μA
I <sub>CC</sub>	V <sub>CC</sub> Operating Supply Current	V <sub>CC</sub> = Max.			110		100	mA
		$I_{OUT} = 0 \text{ mÅ},$ $f = f_{MAX} = 1/t_{RC}$	L		80		70	mA
I <sub>SB1</sub>	Automatic CE	Max. V <sub>CC</sub> , <u>CE</u> ≥ V <sub>IH</sub>			15		15	mA
	Power-Down Current —TTL Inputs	$V_{IN} \ge V_{IH}$ or $V_{IN} \le V_{IL}$ , f = f <sub>MAX</sub>	L		7		7	mA
I <sub>SB2</sub>	Automatic CE	Max. V <sub>CC</sub> ,			1		1	mA
	Power-Down Current —CMOS Inputs	$\begin{array}{l} \overline{\text{CE}} \geq \text{V}_{\text{CC}} - 0.3\text{V}, \\ \text{V}_{\text{IN}} \geq \text{V}_{\text{CC}} - 0.3\text{V}, \\ \text{or } \text{V}_{\text{IN}} \leq 0.3\text{V}, \text{ f=0} \end{array}$	L		100		100	μA

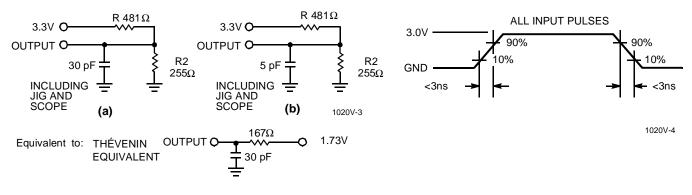
#### Capacitance<sup>[3]</sup>

Parameter	Description	Test Conditions	Max.	Unit
C <sub>IN</sub>	Input Capacitance	$T_A = 25^{\circ}C, f = 1 \text{ MHz},$	8	pF
C <sub>OUT</sub>	Output Capacitance	$V_{CC} = 3.3V$	8	pF

Notes:

3. Tested initially and after any design or process changes that may affect these parameters.

#### AC Test Loads and Waveforms





#### Switching Characteristics<sup>[4]</sup> Over the Operating Range

		7C102	7C1020V-10		7C1020V-12		2 7C1020V-15	
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Unit
READ CYC	LE							
t <sub>RC</sub>	Read Cycle Time	10		12		15		ns
t <sub>AA</sub>	Address to Data Valid		10		12		15	ns
t <sub>OHA</sub>	Data Hold from Address Change	3		3		3		ns
t <sub>ACE</sub>	CE LOW to Data Valid		10		12		15	ns
t <sub>DOE</sub>	OE LOW to Data Valid		5		6		7	ns
t <sub>LZOE</sub>	OE LOW to Low Z	0		0		0		ns
t <sub>HZOE</sub>	OE HIGH to High Z <sup>[5, 6]</sup>		5		6		7	ns
t <sub>LZCE</sub>	CE LOW to Low Z <sup>[6]</sup>	3		3		3		ns
t <sub>HZCE</sub>	CE HIGH to High Z <sup>[5, 6]</sup>		5		6		7	ns
t <sub>PU</sub>	CE LOW to Power-Up	0		0		0		ns
t <sub>PD</sub>	CE HIGH to Power-Down		12		12		15	ns
t <sub>DBE</sub>	Byte enable to Data Valid		5		6		7	ns
t <sub>LZBE</sub>	Byte enable to Low Z	0		0		0		ns
t <sub>HZBE</sub>	Byte disable to High Z		5		6		7	ns
WRITE CYC	LE <sup>[7]</sup>							
t <sub>WC</sub>	Write Cycle Time	10		12		15		ns
t <sub>SCE</sub>	CE LOW to Write End	8		9		10		ns
t <sub>AW</sub>	Address Set-Up to Write End	7		8		10		ns
t <sub>HA</sub>	Address Hold from Write End	0		0		0		ns
t <sub>SA</sub>	Address Set-Up to Write Start	0		0		0		ns
t <sub>PWE</sub>	WE Pulse Width	7		8		10		ns
t <sub>SD</sub>	Data Set-Up to Write End	5		6		10		ns
t <sub>HD</sub>	Data Hold from Write End	0		0		0		ns
t <sub>LZWE</sub>	WE HIGH to Low Z <sup>[6]</sup>	3		3		3		ns
t <sub>HZWE</sub>	WE LOW to High Z <sup>[5, 6]</sup>		5		6		7	ns
t <sub>BW</sub>	Byte enable to end of write	7		8		9		ns

Notes:

Test conditions assume signal transition time of 3 ns or less, timing reference levels of 1.5V, input pulse levels of 0 to 3.0V, and output loading of the specified I<sub>OL</sub>/I<sub>OH</sub> and 30-pF load capacitance. 4.

5.

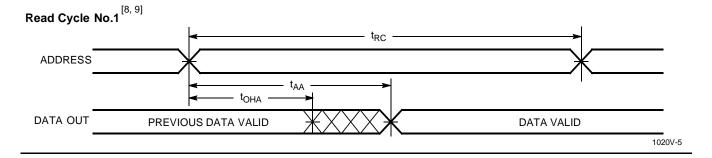
 $t_{HZOE}$ ,  $t_{HZOE}$ ,  $t_{HZOE}$ ,  $t_{HZOE}$ ,  $t_{HZOE}$  and  $t_{HZWE}$  are specified with a load capacitance of 5 pF as in part (b) of AC Test Loads. Transition is measured ±500 mV from steady-state voltage. At any given temperature and voltage condition,  $t_{HZCE}$  is less than  $t_{LZCE}$ ,  $t_{HZOE}$  is less than  $t_{LZOE}$ , and  $t_{HZWE}$  for any given device. The internal write time of the memory is defined by the overlap of CE LOW, WE LOW and BHE / BLE LOW. CE, WE and BHE / BLE must be LOW to initiate a write, and the transition of these signals can terminate the write. The input data set-up and hold timing should be referenced to the leading edge of the signal that terminates the write. 6. 7.



# Switching Characteristics<sup>[4]</sup> Over the Operating Range (continued)

		7C10			
Parameter	Description	Min.	Max.	Unit	
READ CYC	ĹĒ				
t <sub>RC</sub>	Read Cycle Time	20		ns	
t <sub>AA</sub>	Address to Data Valid		20	ns	
t <sub>OHA</sub>	Data Hold from Address Change	3		ns	
t <sub>ACE</sub>	CE LOW to Data Valid		20	ns	
t <sub>DOE</sub>	OE LOW to Data Valid		9	ns	
t <sub>LZOE</sub>	OE LOW to Low Z	0		ns	
t <sub>LZCE</sub>	CE LOW to Low Z <sup>[6]</sup>	3		ns	
t <sub>HZCE</sub>	CE HIGH to High Z <sup>[5, 6]</sup>		9	ns	
t <sub>PU</sub>	CE LOW to Power-Up	0		ns	
t <sub>PD</sub>	CE HIGH to Power-Down		20	ns	
t <sub>DBE</sub>	Byte enable to Data Valid		9	ns	
t <sub>LZBE</sub>	Byte enable to Low Z	0		ns	
t <sub>HZBE</sub>	Byte disable to High Z		9	ns	
WRITE CYC	LE <sup>[7]</sup>				
t <sub>WC</sub>	Write Cycle Time	20		ns	
t <sub>SCE</sub>	CE LOW to Write End	12		ns	
t <sub>AW</sub>	Address Set-Up to Write End	12		ns	
t <sub>HA</sub>	Address Hold from Write End	0		ns	
t <sub>SA</sub>	Address Set-Up to Write Start	0		ns	
t <sub>PWE</sub>	WE Pulse Width	12		ns	
t <sub>SD</sub>	Data Set-Up to Write End	10		ns	
t <sub>HD</sub>	Data Hold from Write End	0		ns	
t <sub>LZWE</sub>	WE HIGH to Low Z <sup>[6]</sup>	3		ns	
t <sub>HZWE</sub>	WE LOW to High Z <sup>[5, 6]</sup>		9	ns	
t <sub>BW</sub>	Byte enable to end of write	12		ns	

# Switching Waveforms



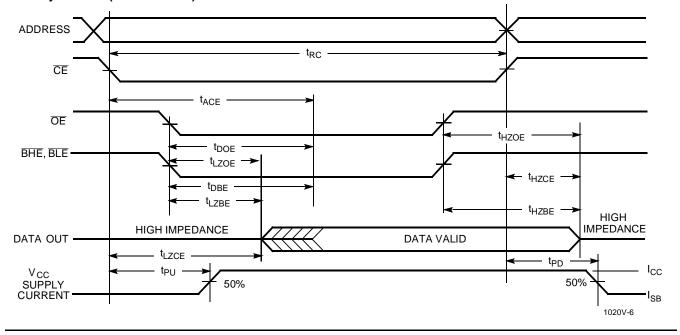
Notes:

8. Device is continuously selected.  $\overline{OE}$ ,  $\overline{CE}$ ,  $\overline{BHE}$ , and/or  $\overline{BHE} = V_{IL}$ 9. WE is HIGH for read cycle.

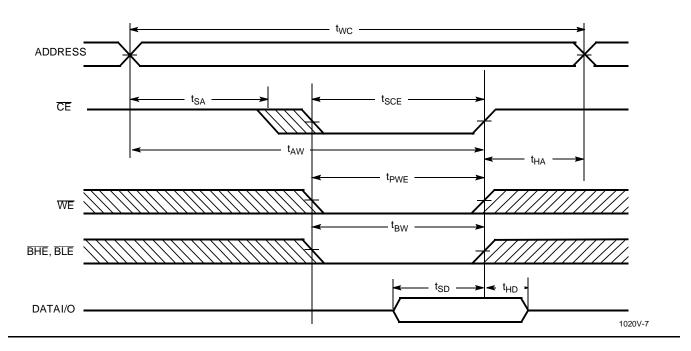


#### Switching Waveforms (continued)

# Read Cycle No.2 ( $\overline{\text{OE}}$ Controlled) <sup>[9, 10]</sup>



Write Cycle No. 1 (CE Controlled)<sup>[11, 12]</sup>



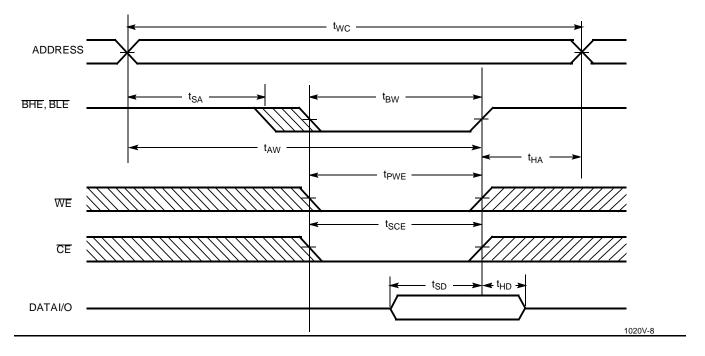
#### Notes:

Address valid prior to or coincident with CE transition LOW.
Data I/O is high impedance if OE or BHE and/or BLE= V<sub>IH</sub>.
If CE goes HIGH simultaneously with WE going HIGH, the output remains in a high-impedance state.

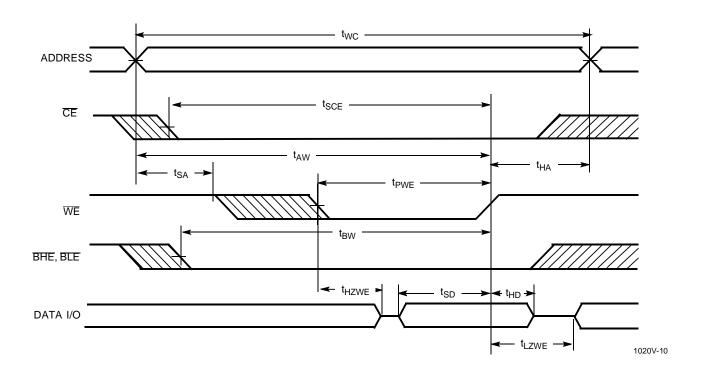


### Switching Waveforms (continued)





Write Cycle No.3 (WE Controlled, OE LOW)





# Truth Table

CE	OE	WE	BLE	BHE	<b>I/O<sub>1</sub> - I/O<sub>8</sub></b>	I/O <sub>9</sub> - I/O <sub>16</sub>	Mode	Power
Н	Х	Х	Х	Х	High Z	High Z	Power-Down	Standby (I <sub>SB</sub> )
L	L	Н	L	L	Data Out	Data Out	Read - All bits	Active (I <sub>CC</sub> )
			L	Н	Data Out	High Z	Read - Lower bits only	Active (I <sub>CC</sub> )
			Н	L	High Z	Data Out	Read - Upper bits only	Active (I <sub>CC</sub> )
L	Х	L	L	L	Data In	Data In	Write - All bits	Active (I <sub>CC</sub> )
			L	Н	Data In	High Z	Write - Lower bits only	Active (I <sub>CC</sub> )
			Н	L	High Z	Data In	Write - Upper bits only	Active (I <sub>CC</sub> )
L	Н	Н	Х	Х	High Z	High Z	Selected, Outputs Disabled	Active (I <sub>CC</sub> )
L	Х	Х	Н	Н	High Z	High Z	Selected, Outputs Disabled	Active (I <sub>CC</sub> )

# **Ordering Information**

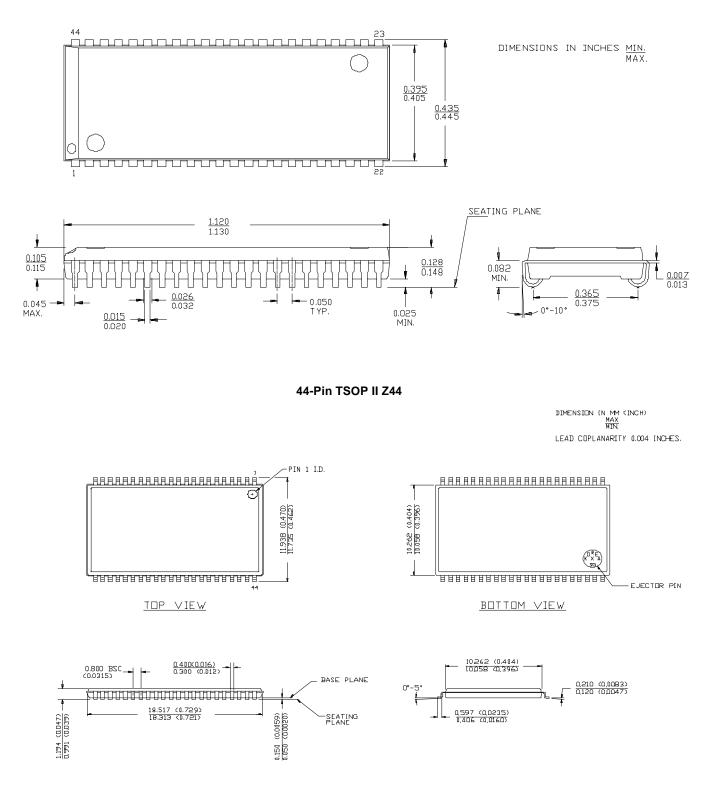
Speed (ns)	Ordering Code	Package Name	Package Type	Operating Range
10	CY7C1020V33-10VC	V34	44-Lead (400-Mil) Molded SOJ	Commercial
	CY7C1020V33L-10VC	V34	44-Lead (400-Mil) Molded SOJ	Commercial
	CY7C1020V33-10ZC	Z44	44-Lead TSOP Type II	Commercial
	CY7C1020V33L-10ZC	Z44	44-Lead TSOP Type II	Commercial
12	CY7C1020V33-12VC	V34	44-Lead (400-Mil) Molded SOJ	Commercial
	CY7C1020V33L-12VC	V34	44-Lead (400-Mil) Molded SOJ	Commercial
	CY7C1020V33-12ZC	Z44	44-Lead TSOP Type II	Commercial
	CY7C1020V33L-12ZC	Z44	44-Lead TSOP Type II	Commercial
15	CY7C1020V33-15VC	V34	44-Lead (400-Mil) Molded SOJ	Commercial
	CY7C1020V33L-15VC	V34	44-Lead (400-Mil) Molded SOJ	Commercial
	CY7C1020V33-15ZC	Z44	44-Lead TSOP Type II	Commercial
	CY7C1020V33L-15ZC	Z44	44-Lead TSOP Type II	Commercial
	CY7C1020V33-15ZI	Z44	44-Lead TSOP Type II	Industrial
20	CY7C1020V33L-20ZC	Z44	44-Lead TSOP Type II	Commercial

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Package Diagrams

44-Lead (400-Mil) Molded SOJ V34



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